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Prelim. Amdt. dated 27 May 2004
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IN THE CLAIMS:

1. (Currently Amended) An inspecting system comprising:

an analyzing unit, said analyzing unit including an image detection device for producing a plurality of images of a workpiece;

storage means for storing ~~detected~~ said plurality of images produced by said image detection device and classification information;

display means having a screen with a first area for displaying ~~a~~ said plurality of ~~said detected~~ images stored in said storage means that have not been classified and a plurality of second areas for displaying selected classification information and for initially classifying ~~and displaying~~ said ~~detected~~ images according to features of said ~~detected~~ images; and

means for moving said plurality of detected images on said screen from said first area to selected second areas to classify and display said ~~detected~~ images in said second areas.

2. (Currently Amended) An analyzing unit comprising:

storage means for storing a plurality of images and classification information;

display means having a screen with a first area for displaying said plurality of images stored in said storage means that have not been classified and a plurality of second areas for displaying selected classification information and for initially classifying ~~and displaying~~ said images according to features of said images; and

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means for moving ones of said plurality of images on said screen from said first area to selected second areas to classify and display said plurality of images in said second areas.

3. (Currently Amended) A method of manufacturing an electronic device, wherein use is made of a manufacturing apparatus for processing a workpiece to form an electronic device, an inspecting apparatus for inspecting the workpiece processed by said manufacturing apparatus, an analyzing unit including an image detection device which is capable of producing ~~an image~~ a plurality of images of said workpiece, and a storage means for storing said images of ~~workpieces~~ said workpiece detected by said image detection device and other information, the method comprising:

displaying ~~detected~~ said plurality of images stored in said storage means on a first area of a screen, the screen having a plurality of second areas containing selected other information for classifying and displaying said detected images according to features of said ~~detected~~ images;

moving ones of said ~~detected~~ images on said screen from said first area to selected second areas to classify and display said detected images in said second areas;

providing information to said analyzing unit concerning images in said second areas of said screen; and

controlling the production line having said manufacturing apparatus arranged thereon using information obtained from said analyzing unit.

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4. (Currently Amended) An Inspecting system comprising:

an analyzing unit, said analyzing unit including an image detection device to produce images of semiconductor manufacturing defects for a workpiece;

a display with a sorting display area in which to display ones of said images with unclassified semiconductor manufacturing defects, and a plurality of defect-classification display areas into which each image of said images may be classified and displayed according to visual manufacturing defect features contained in the image; and

a user-manipulated moving unit to move a~subject~ an image from said sorting display area to a~ selected ~one~ ones of said defect-classification display areas, to classify and display said subject image ~into~ in the selected ~one~ ones of said defect-classification display areas.

5. (Currently Amended) An inspecting system as claimed in claim 4, wherein the user-manipulated moving unit includes a user-manipulated pointing device to point to, select and drag-and-drop said ~subject~ image from said sorting display area into ~the~ selected ~one~ ones of said defect-classification display areas.

6. (Previously Presented) An inspecting system as claimed in claim 5, wherein said user-manipulated pointing device is a mouse.

7. (Currently Amended) An inspecting system as claimed in claim 4, comprising a memory to store predetermined information for at least ones of said

images including defect-classification information, and an adjuster unit to adjust said

defect-classification information for said ~~subject image~~ images to match a defect

classification of the selected one of said defect-classification display areas to which

said ~~subject image is~~ images are moved.

    8. (Currently Amended) An inspecting method, comprising:

    using an image detection device to produce images of semiconductor

manufacturing defects ~~for~~ in a workpiece;

    displaying images of unclassified semiconductor manufacturing defects within

a sorting display area of a display, and displaying a plurality of defect-classification

display areas into which each image of said images may be classified and displayed

according to visual manufacturing defect features contained in the ~~image~~ images;

and

    user-manipulated moving of a subject image from said sorting display area to

a selected ~~one~~ ones of said defect-classification display areas, to classify and

display each said ~~subject~~ image ~~into~~ in the selected one of said defect-classification

display areas.

    9. (Currently Amended) An inspecting method as claimed in claim 8, wherein

said user-manipulated moving is effected with a user-manipulated pointing device to

point to, select and drag-and-drop said ~~subject image~~ images from said sorting

display area into the selected ~~one~~ ones of said defect-classification display areas.

10. (Previously Presented) An inspecting method as claimed in claim 9,

wherein said user-manipulated pointing device is a mouse.

11. (Currently Amended) An inspecting method as claimed in claim 8,

comprising:

storing predetermined information for at least ones of said images including

defect-classification information in a memory; and

adjusting said defect-classification information for said subject image to

match a defect classification of the selected one of said defect-classification display

areas to which said ~~subject image is~~ images are moved.